Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	_
09/512,276	NAGAO ET AL.	
Examiner	Art Unit	_
Louis K. Huyah	3721	

SEARCHED			
Class	Subclass	Date	Examiner
206	408 446 522 591 594	4/16/2002	LT
53	472 449	4/16/2002	LT
Updated	All above	2/4/2003	LT
53	139.5 49	11/22/2005	LH
53	449 444 409	11/22/2005	LH
206	419 421	11/28/2005	LH
Updated	All above	12/22/2005	LH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Consulted with John Sipos (class 53) David Fidei (class 206)	4/16/2002	LT
EAST text search "glass base material"	2/11/2003	LT